Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/088,281	HAYASHI ET AL.
Examiner	Art Unit
l <b></b>	1.544

SEARCHED				
Class	Subclass	Date	Examiner	
Class	Subciass	Date	Cxammer	
524	145	5/18/2005	МОН	
524	781	5/18/2005	МОН	
252	582	5/18/2005	MQH	
523	136	5/18/2005	МОН	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
524	145	5/18/2005	MQH
As a	rbove	11-8-05	DG.

SEARCH N (INCLUDING SEARC		0
	DATE	EXMR
Inventor search	5/18/2005	мон
EAST search attached	5/18/2005	мон
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